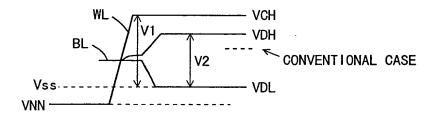
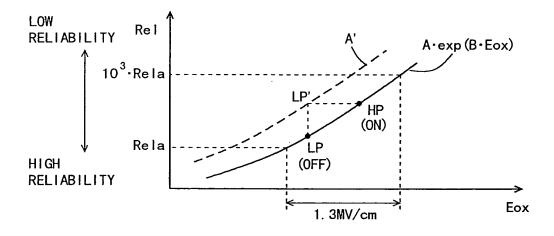
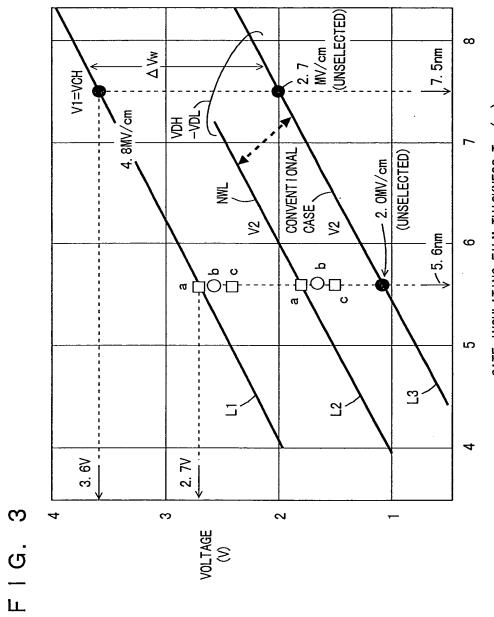
F I G. 1



F I G. 2





GATE INSULATING FILM THICKNESS Tox (nm)

F I G. 4

	VCH	Vcca	VNN	Eox1	Eox2
a:	2. 7V	1. 8V	-0. 8V	4.8M	4. 6M
b:	2. 55V	1. 65V	-0. 65V	4. 6M	4. 1M
c:	2. 4V	1. 5V	-0. 5V	4. 3M	3.6M
}					

FIG. 9

	VCH	VDH	Vbsg	Eox1	Eox2
d	2. 7V	1. 8V	OV	4. 8M	3. 2M
е	2. 7V 2. 7V	1. 8V	0. 3V	4. 3M	3. 2M
f	2. 7V	1. 8V	0. 5V	3.9M	3. 2M

F I G. 5

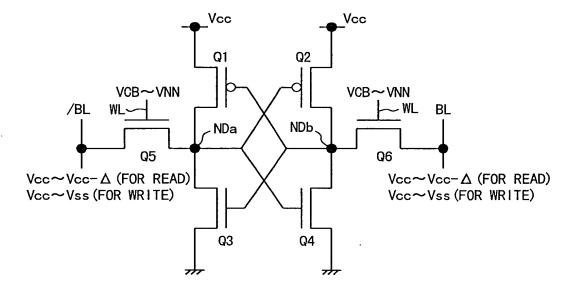


FIG. 6

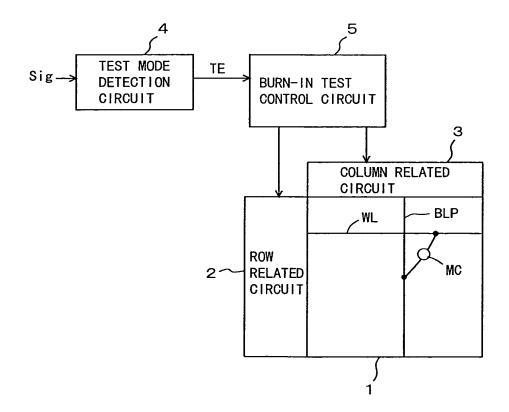


FIG. 7A

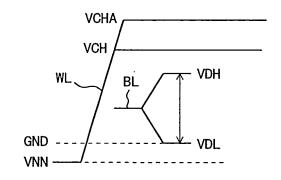


FIG. 7B

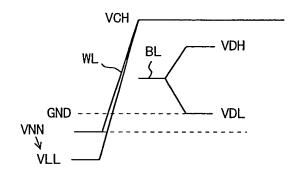
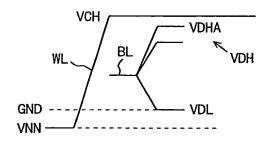


FIG. 7C



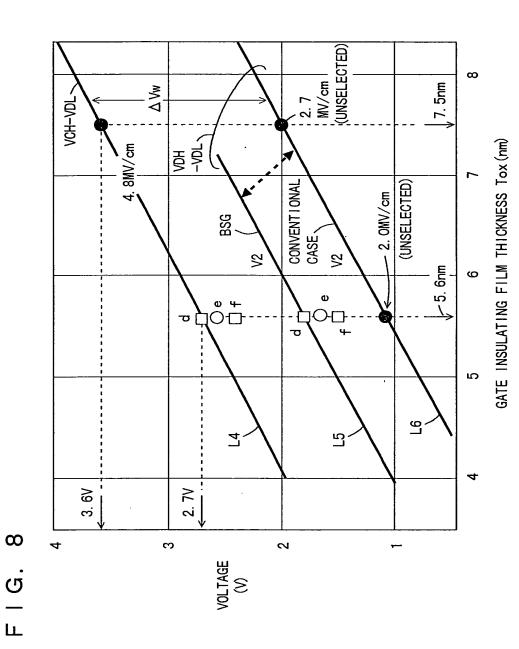


FIG. 10A

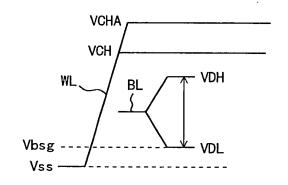


FIG. 10B

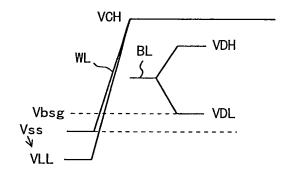


FIG. 10C

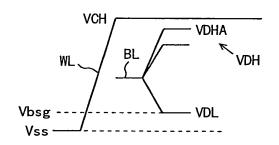


FIG. 11

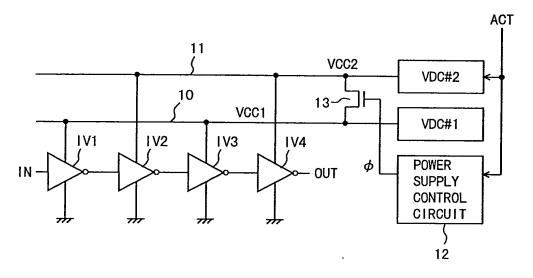
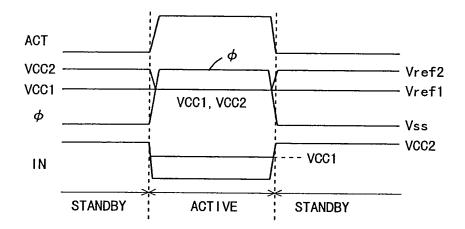


FIG. 12



F I G. 13A FIG. 13B 11 Ζφ --Vref3 VCC1, VCC2 -Vref2 VCC2 VCC1 -Vref1 10 } Zφ STANDBY 1 ACTIVE STANDBY

FIG. 14

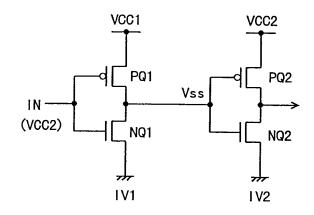


FIG. 15

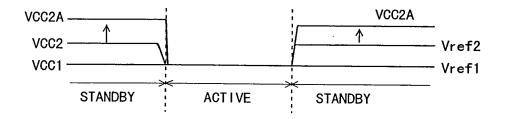


FIG. 16

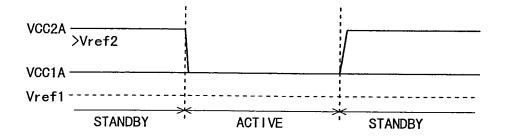


FIG. 17

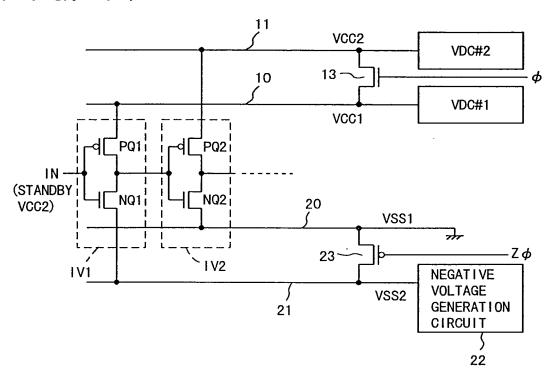


FIG. 18

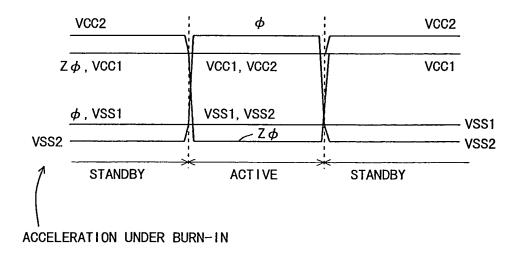


FIG. 19

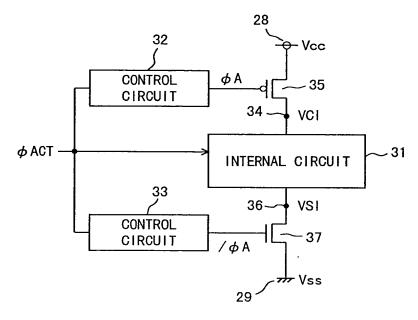


FIG. 20

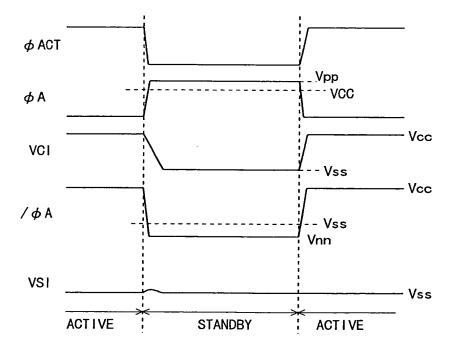


FIG. 21

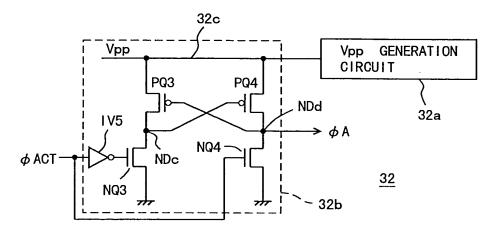


FIG. 22

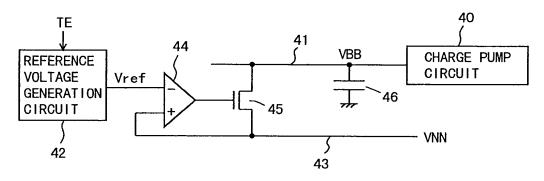


FIG. 23

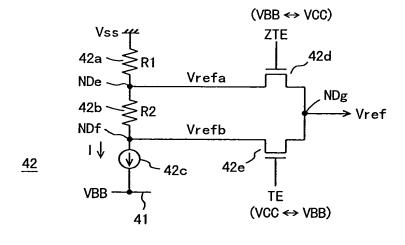


FIG. 24

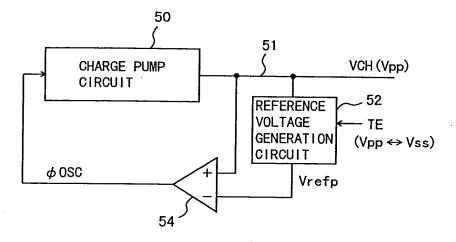


FIG. 25

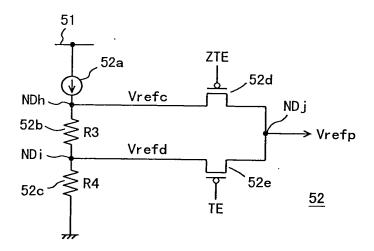


FIG. 26

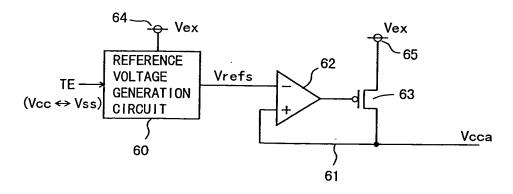


FIG. 27 PRIOR ART

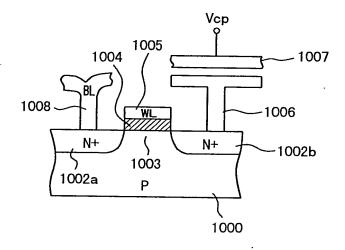


FIG. 28A PRIOR ART

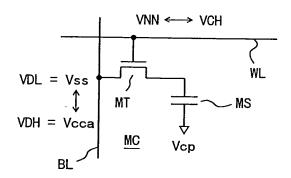


FIG. 28B PRIOR ART

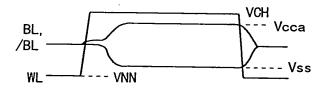


FIG. 29A PRIOR ART

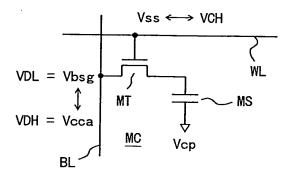


FIG. 29B PRIOR ART

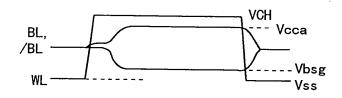


FIG. 30 PRIOR ART

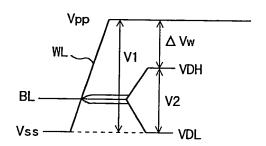
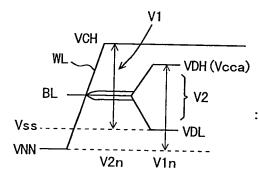
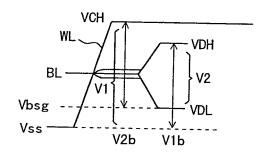


FIG. 31 PRIOR ART



: SAME AS CONVENTIONAL CASE, ASSURING OF RELIABILITY BY CONSIDERING V1 AND V2

FIG. 32 PRIOR ART



: SAME AS CONVENTIONAL CASE, ASSURING OF RELIABILITY BY CONSIDERING V1 AND V2

FIG. 33 PRIOR ART

